Amendments to the Specification

Please replace the paragraph beginning on page 41, line 17, with the following rewritten paragraph:

As described in the second embodiment, the reference light beam always comes into the interference fringe-detecting section in the alignment mode. Therefore, when the test sample 109 is inserted, any interference fringe can be necessarily observed. It is easy to perform the alignment adjustment for the test sample 109 in order to obtain the interference fringes optimum for the measurement. According to the fact as described above, the point diffraction interference measuring apparatus according to the ~~third embodiment~~ second embodiment (alignment mode) is principally used for the alignment adjustment for the test sample 109.

Please replace the paragraph beginning on page 42, line 19, with the following rewritten paragraph:

(2) The position of the returning mirror M is adjusted three-dimensionally so that the contrast is satisfactory to give the interference fringes in the state optimum for the measurement. More specifically, the position of the mirror M is adjusted three-dimensionally to give the state in which the best interference fringes to be successfully formed by the optical arrangement of the apparatus shown in Fig. 5 are obtained, specifically to obtain the most ideal interference fringes formed such that the reference light beam having a sufficient light amount passes across the pinhole 129 to mutually cause the interference between the reference light beam and the measuring light beam thereby. The power component and the tilt component (alignment information) in the phase difference between the measuring light beam and the reference light beam are determined with the aid of the computer analysis from the result of the measurement of the most ideal interference fringes obtained by the adjustment, which are stored as base (target) data in the analyzing computer equipped for the

interference fringe-detecting ~~section 118~~ section 115.

Please replace the paragraph beginning on page 51, line 4, with the following rewritten paragraph:

When the measurement is performed in the measurement mode by using the point diffraction interference measuring apparatus according to this embodiment, then the light flux, which has outgone from the light source 101, is prevented from passing across the optical path length difference-correcting section H (see Fig. 3) by rotating (adjusting) the 1/2 wavelength plate 161, and thus it is possible to mitigate the loss of the light amount.